

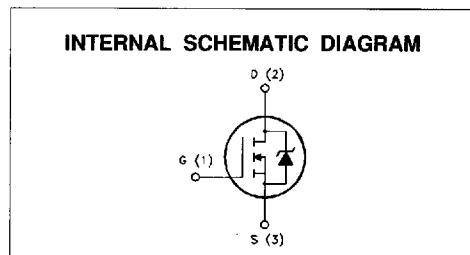
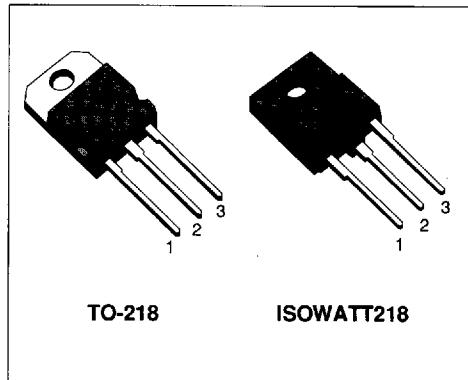

**N - CHANNEL ENHANCEMENT MODE
POWER MOS TRANSISTOR**

TYPE	V _{DSS}	R _{DS(on)}	I _D
STH4N80	800 V	< 3 Ω	4.3 A
STH4N80FI	800 V	< 3 Ω	2.8 A

- TYPICAL R_{DS(on)} = 2.5 Ω
- AVALANCHE RUGGED TECHNOLOGY
- 100% AVALANCHE TESTED
- REPETITIVE AVALANCHE DATA AT 100°C
- LOW INPUT CAPACITANCE
- LOW GATE CHARGE
- APPLICATION ORIENTED CHARACTERIZATION

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- CONSUMER AND INDUSTRIAL LIGHTING
- DC-AC INVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLY (UPS)

**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value		Unit
		STH4N80	STH4N80FI	
V _{DS}	Drain-source Voltage (V _{GS} = 0)	800	—	V
V _{DGR}	Drain-gate Voltage (R _{GS} = 20 kΩ)	800	—	V
V _{GS}	Gate-source Voltage	—	± 20	V
I _D	Drain Current (continuous) at T _c = 25 °C	4.3	2.8	A
I _D	Drain Current (continuous) at T _c = 100 °C	2.6	1.7	A
I _{DM(•)}	Drain Current (pulsed)	16	16	A
P _{tot}	Total Dissipation at T _c = 25 °C	125	55	W
	Derating Factor	1	0.44	W/°C
V _{ISO}	Insulation Withstand Voltage (DC)	—	4000	V
T _{stg}	Storage Temperature	—	-65 to 150	°C
T _j	Max. Operating Junction Temperature	—	150	°C

(•) Pulse width limited by safe operating area

THERMAL DATA

			TO-218	ISOWATT218	
R _{th-case}	Thermal Resistance Junction-case	Max	1	2.27	°C/W
R _{th-amb}	Thermal Resistance Junction-ambient	Max	30		°C/W
R _{thc-sink}	Thermal Resistance Case-sink	Typ	0.1		°C/W
T _j	Maximum Lead Temperature For Soldering Purpose		300		°C

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T _j max, δ < 1%)	4.3	A
E _{AS}	Single Pulse Avalanche Energy (starting T _j = 25 °C, I _D = I _{AR} , V _{DD} = 50 V)	230	mJ
E _{AR}	Repetitive Avalanche Energy (pulse width limited by T _j max, δ < 1%)	10	mJ
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (T _c = 100 °C, pulse width limited by T _j max, δ < 1%)	2.6	A

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 μA V _{GS} = 0	800			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating × 0.8 T _c = 125 °C			250 1000	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20 V			± 100	nA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} I _D = 250 μA	2	3	4	V
R _{DSS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V I _D = 1.7 A V _{GS} = 10 V I _D = 1.7 A T _c = 100 °C		2.5	3 6	Ω Ω
I _{D(on)}	On State Drain Current	V _{DS} > I _{D(on)} × R _{DSS(on)max} V _{GS} = 10 V	4.3			A

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _{fs} (*)	Forward Transconductance	V _{DS} > I _{D(on)} × R _{DSS(on)max} I _D = 1.7 A	1			S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V f = 1 MHz V _{GS} = 0			1100 150 55	pF pF pF

ELECTRICAL CHARACTERISTICS (continued)**SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on Time Rise Time	$V_{DD} = 30 \text{ V}$ $I_D = 2.3 \text{ A}$ $R_G = 50 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 3)		65 150	90 200	ns ns
$(di/dt)_{on}$	Turn-on Current Slope	$V_{DD} = 600 \text{ V}$ $I_D = 3.8 \text{ A}$ $R_G = 50 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 5)		80	110	A/ μs
Q_g Q_{gs} Q_{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 400 \text{ V}$ $I_D = 5 \text{ A}$ $V_{GS} = 10 \text{ V}$		55 8 26	70	nC nC nC

SWITCHING OFF

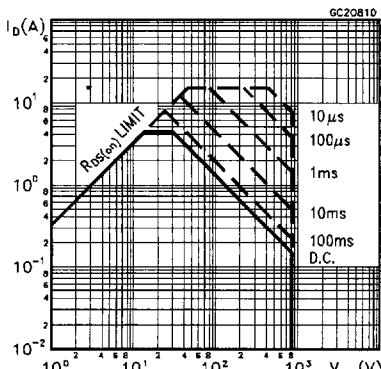
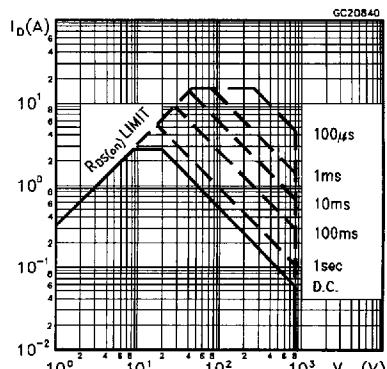
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{r(Voff)}$ t_f t_c	Off-voltage Rise Time Fall Time Cross-over Time	$V_{DD} = 600 \text{ V}$ $I_D = 3.8 \text{ A}$ $R_G = 50 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 5)		110 140 150	145 190 200	ns ns ns

SOURCE DRAIN DIODE

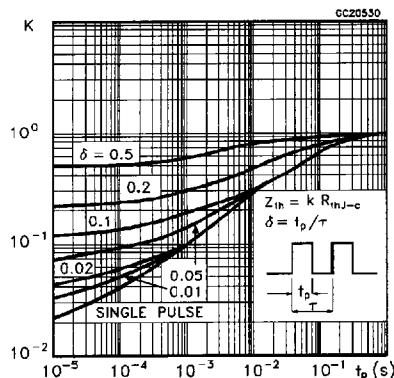
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD} $I_{SDM}(\bullet)$	Source-drain Current Source-drain Current (pulsed)				4.2 16	A A
V_{SD} (*)	Forward On Voltage	$I_{SD} = 4.3 \text{ A}$ $V_{GS} = 0$			2	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 3.8 \text{ A}$ $di/dt = 100 \text{ A}/\mu\text{s}$		500		ns
Q_{rr}	Reverse Recovery Charge	$V_R = 100 \text{ V}$ $T_j = 150^\circ\text{C}$ (see test circuit, figure 5)		4.3		μC
I_{RRM}	Reverse Recovery Current			17		A

(*) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %

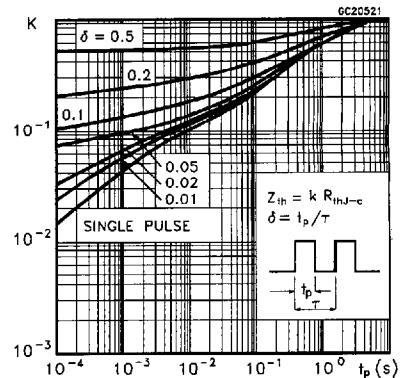
(*) Pulse width limited by safe operating area

Safe Operating Areas For TO-218**Safe Operating Areas For ISOWATT218**

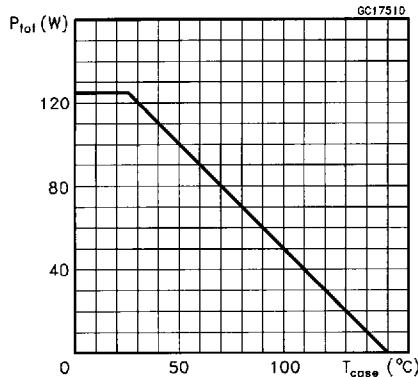
Thermal Impedance For TO-218



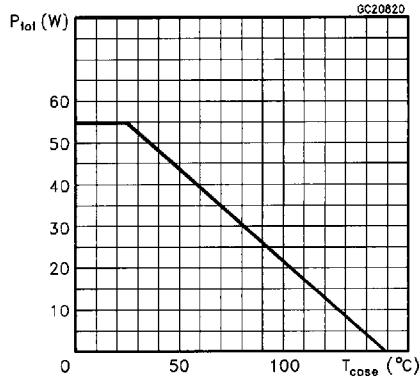
Thermal Impedance For ISOWATT218



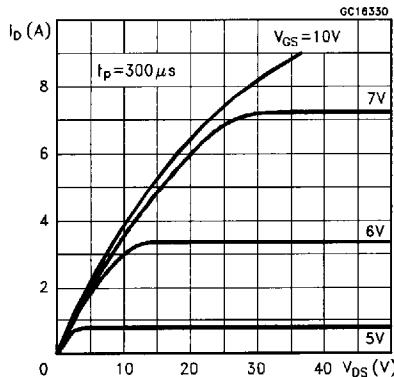
Derating Curve For TO-218



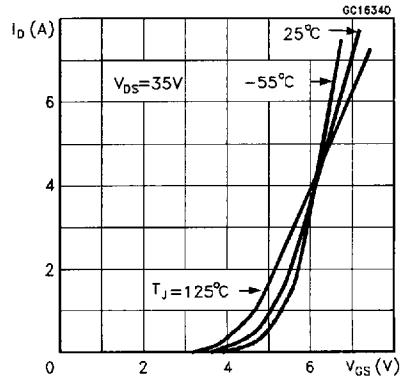
Derating Curve For ISOWATT218



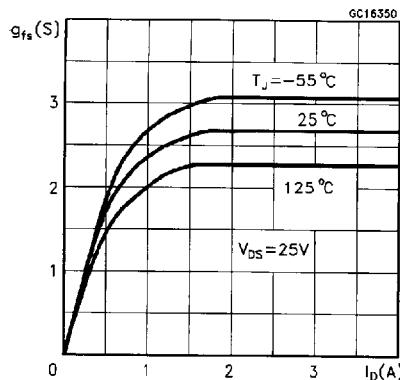
Output Characteristics



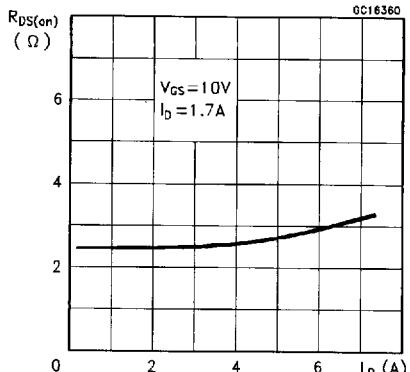
Transfer Characteristics



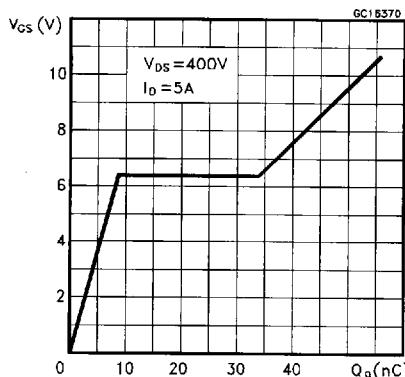
Transconductance



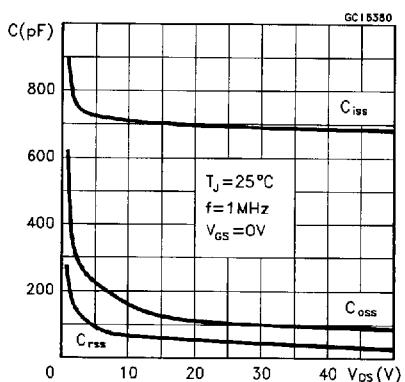
Static Drain-source On Resistance



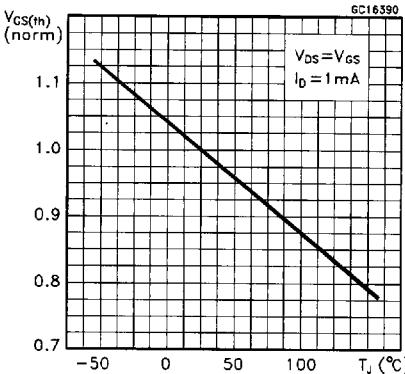
Gate Charge vs Gate-source Voltage



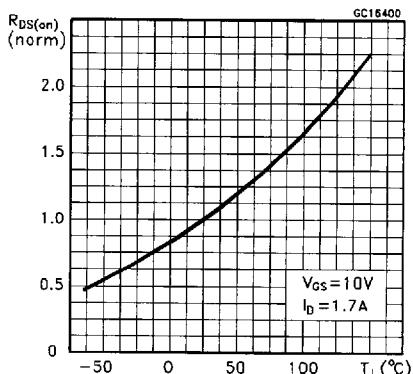
Capacitance Variations



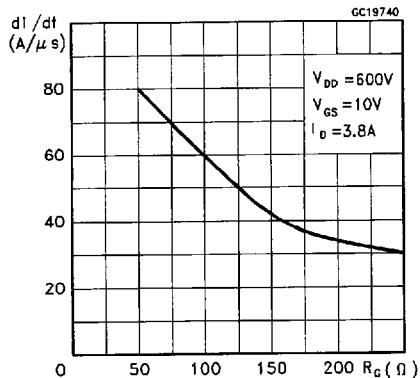
Normalized Gate Threshold Voltage vs Temperature



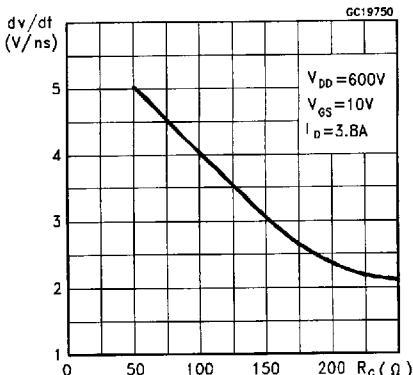
Normalized On Resistance vs Temperature



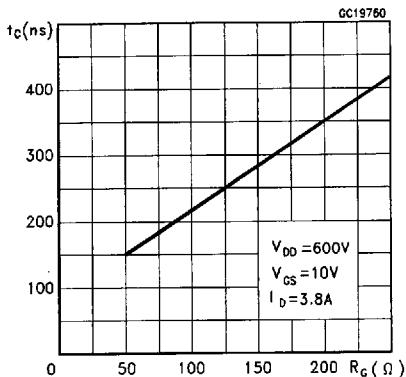
Turn-on Current Slope



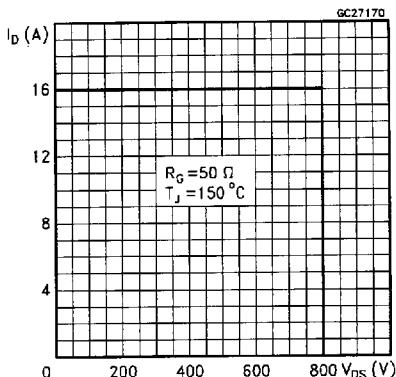
Turn-off Drain-source Voltage Slope



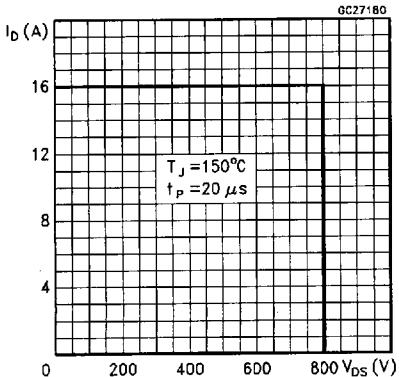
Cross-over Time



Switching Safe Operating Area



Accidental Overload Area



Source-drain Diode Forward Characteristics

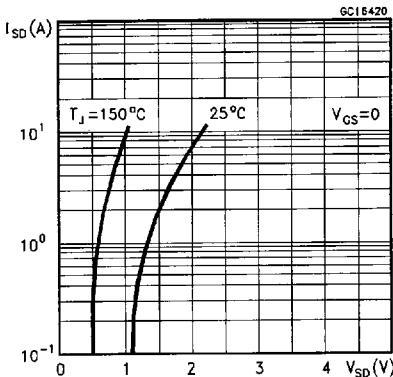
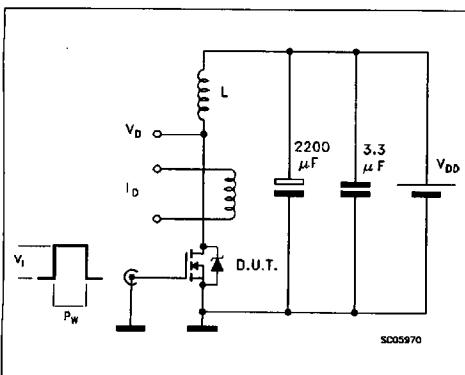
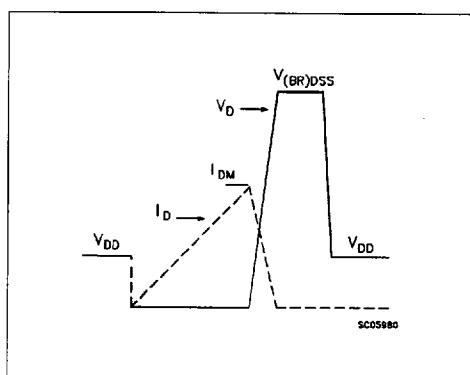
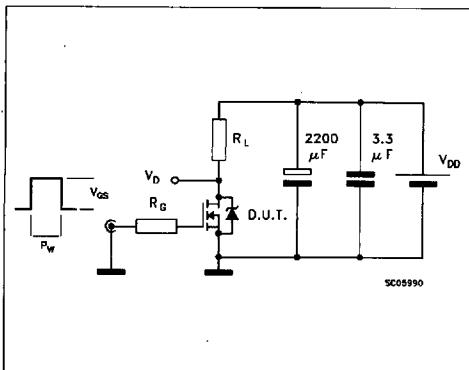
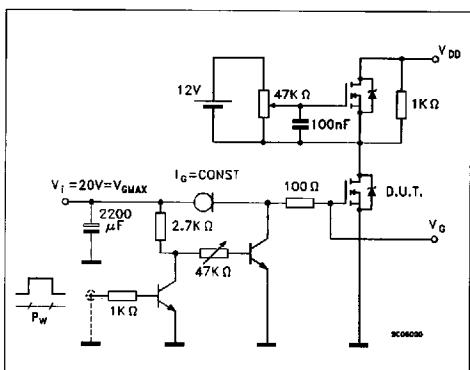


Fig. 1: Unclamped Inductive Load Test Circuits**Fig. 2: Unclamped Inductive Waveforms****Fig. 3: Switching Times Test Circuits For Resistive Load****Fig. 4: Gate Charge Test Circuit****Fig. 5: Test Circuit For Inductive Load Switching And Diode Reverse Recovery Time**